

Form PTO-1449

U.S. DEPARTMENT OF COMMERCE
PATENT AND TRADEMARK OFFICEATTY. DOCKET NO.
M122-532SERIAL NO.
09 332,271LIST OF ART CITED BY APPLICANT
(Use several sheets if necessary)APPLICANT
Klaus Florian SchuegrafFILING DATE
June 11, 1999GROUP
2812

U.S. PATENT DOCUMENTS

*Examiner Initial		Document Number	Date	Name	Class	Subclass	Filing Date If Appropriate
RP	AA	5,472,896	12 95	Chen et al.	437	44	
RP	AB	5,393,685	02 95	Yoo et al.	437	44	
RP	AC	4,833,099	05 89	Woo	437	41	
	AD	5,915,197	06 99	Yamanaka et al.	438	586	
	AE						
	AF						
	AG						
	AH						
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	AJ						
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FOREIGN PATENT DOCUMENTS

		Document Number	Date	Country	Class	Subclass	Translation	
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OTHER REFERENCES (including Author, Title, Date, Pertinent Pages, Etc.)

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PATENT AND TRADEMARK OFFICEATTY. DOCKET NO.
MJ22-532SERIAL NO.
09/332,271

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LIST OF ART CITED BY APPLICANT
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June 11, 1999GROUP
2312

U.S. PATENT DOCUMENTS

*Examiner Initial		Document Number	Date	Name	Class	Subclass	Filing Date If Appropriate
RP	AA	4,354,309	10/1982	Gardiner et al.			
RP	AB	4,559,091	12/1985	Allen et al.	148	174	
RP	AC	4,886,765	12/1989	Chen et al.	437	200	
RP	AD	5,192,708	03/1993	Beyer et al.	437	90	
RP	AE	5,393,676	02/1995	Anjum et al.	437	24	
RP	AF	5,712,181	01/1998	Byun et al.	437	46	
RP	AG	5,798,296	08/1998	Fazan et al.	438	592	
RP	AH	5,811,343	09/1998	Wann et al.	438	305	
RP	AI	5,985,720	11/1999	Saitoh	438	266	
RP	AJ	6,040,238	03/2000	Yang et al.	438	592	
RP	AK	5,164,333	11/1992	Schwalke et al.	437	200	
RP	AL						

FOREIGN PATENT DOCUMENTS

		Document Number	Date	Country	Class	Subclass	Translation	
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	AM	JP 02265248 A	04/1989	Japan - Kurivama, Hiroko				
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OTHER REFERENCES (including Author, Title, Date, Pertinent Pages, Etc.)

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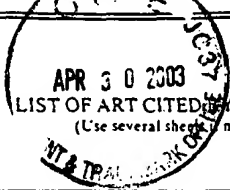
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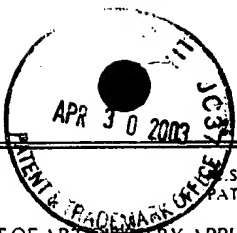
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APPLICANT Klaus Florian Schuegraf						FILING DATE June 11, 1999		GROUP 2812	
U.S. PATENT DOCUMENTS									
*Examiner Initial		Document Number	Date	Name	Class	Subclass	Filing Date If Appropriate		
RD	AA	5,350,698	09/1994	Huang et al.	437	26			
RD	AB	5,441,904	08/1995	Kim et al.	437	40			
RD	AC	5,481,128	01/1996	Hong	257	320			
RD	AD	6,060,741	05/2000	Huang	257	315			
RD	AE	6,208,004 B1	03/2001	Cunningham	257	413			
RD	AF	6,239,458 B1	05/2001	Liaw et al.	257	296			
RD	AG	5,767,004	06/98	Balasubramanian et al.					
RD	AH	5,840,607	11/98	Yeh et al.					
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FOREIGN PATENT DOCUMENTS									
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EXAMINER <i>km Pompey</i>					DATE CONSIDERED <i>7-8-03</i>				
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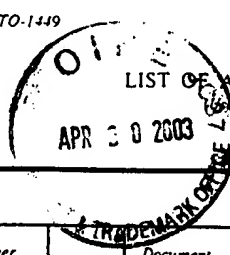


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Sheet 1 of 1

Form PTO-1449		U.S. DEPARTMENT OF COMMERCE PATENT AND TRADEMARK OFFICE		ATTY. DOCKET NO. MI22-532		SERIAL NO. 09 332,271		
LIST OF ART CITED BY APPLICANT (Use several sheets if necessary)				APPLICANT Klaus Florian Schuegraf				
				FILING DATE June 11, 1999		GROUP 2312		
U.S. PATENT DOCUMENTS								
*Examiner Initial		Document Number	Date	Name	Class	Subclass	Filing Date If Appropriate	
RD	AA	6,130,145	10/2000	Ilg et al.	438	592		
RD	AB	5,818,092	10/1998	Bai et al.	257	388		
RD	AC	6,262,458 B1	07/2001	Hu	257	384		
RD	AD	5,986,312	11/1999	Kuroda	257	382		
RD	AE	5,723,893	03/1998	Yu et al.	257	413		
RD	AF	5,710,454	01/1998	Wu	257	413		
RD	AG	5,650,648	07/1997	Kapoor	257	316		
RD	AH	5,425,392	06/1995	Thakur et al.	437	173		
RD	AI	5,256,894	10/1993	Shino	257	388		
RD	AJ	5,053,351	10/1991	Fazan et al.	437	52		
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FOREIGN PATENT DOCUMENTS								
		Document Number	Date	Country	Class	Subclass	Translation	
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OTHER REFERENCES (including Author, Title, Date, Pertinent Pages, Etc.)								
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EXAMINER <i>Rm Pompey</i>				DATE CONSIDERED <i>7-8-03</i>				
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Form PTO-1449		U.S. DEPARTMENT OF COMMERCE PATENT AND TRADEMARK OFFICE		ATTORNEY: CKET NO. MJ22-532		SERIAL NO. Unknown	
 <p>LIST OF ART CITED BY APPLICANT (on several sheets if necessary)</p>				APPLICANT Klaus Florian Schuegraf et al.		FILING DATE Filed herewith	
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U.S. PATENT DOCUMENTS							
*Examiner Initial	Document Number	Date	Name	Class	Subclass	Filing Date If Appropriate	
RP	AA 5,425,392	06/95	Thakur et al.				
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FOREIGN PATENT DOCUMENTS							
	Document Number	Date	Country	Class	Subclass	Translation	
						Yes	No
	AL						
OTHER REFERENCES (including Author, Title, Date, Pertinent Pages, Etc.)							
RP	AK		Taisi Kubota et al.; "The Effect of the Floating Gate/Tunnel SiO ₂ Interface on FLASH Memory Data Retention Reliability"; 1994; 2 pages				
RP	AL		Shoue Jen Wang et al.; "Effects of Poly Depletion on the Estimate of Thin Dielectric Lifetime"; IEEE Electron Device Letters, Vol. 12, No. 11, November 1991; pp. 617-619				
RP	AM		Klaus F. Schuegraf et al.; "Impact of Polysilicon Depletion in Thin Oxide MOS Technology"; 1993; pp. 86-88				
RP	AV		E. H. Snow et al.; "Polarization Phenomena and Other Properties of Phosphosilicate Glass Films on Silicon"; Journal of the Electrochemical Society, March 1966; pp. 263-269				
EXAMINER <i>hm bampedy</i>				DATE CONSIDERED <i>7-8-03</i>			
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